

Search Notes



Application No.

10/752,621

Examiner

Peguy JeanPierre

Applicant(s)

LEUNG, KA Y.

Art Unit

2819

SEARCHED

Class	Subclass	Date	Examiner
341	118	9/7/2004	PJP
	120	/	/
	155	/	/
	172	/	/
update search 9/10 PJP			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
341	155	12/10/04	PJP
	172	/	/

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
east	9/7/2004	PJP
differential comparator with ratiometric bias circuit	/	/